

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10084258	HEGDE ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Stork, Kyle R	2178	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
715	513, 517, 523, 530	6/28/07	
715	234, 243, 254, 255	5/14/08	
715	234, 243, 254, 255	10/28/08	
715	234, 243, 254, 255	3/28/09	

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Update EAST Search (USPat, USPG-Pub)	6/28/07	
NPL Search (IEEE, ACM, Google)	6/27/08	
Update EAST Search (USPat, USPG-Pub)	5/14/08	
NPL Search (IEEE, ACM, Google)	5/14/08	
Update EAST Search (USPat, USPG-Pub)	10/28/08	
Update NPL Search (IEEE, ACM, Google, Safari)	10/28/08	
Update EAST Search (USPat, USPG-Pub)	3/28/09	
Update NPL Search (IEEE, ACM, Google, Safari)	3/28/09	

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

	/K. R. S./ Examiner Art Unit 2178
--	--------------------------------------